Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/687,643	MINO, TETSUYA
Examiner	Art Unit
Paul D. Kim	3729

SEARCHED					
Class	Subclass	Date	Examiner		
29	603.11 603.13- 603.16 603.18	7/5/2005	PK		
360	121 122	7/5/2005	PK		
	126 317				
427	127 128				
204	192.32- 19	7/5/2005	PK		
216	22				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		<u> </u>			

SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
Reviewed Parent Application 09/150,206 (US PAT. 6,188,544) 09/734,758 (ABN)	7/5/2005	PK
Textr Search EAST/NPL (IEEE)	7/6/2005	PK
Updated Text Search (EAST)	11/14/2005	PK
Updated Text Search EAST	3/14/2006	PK
Updated Text Search EAST	5/31/2006	PK